

MRLM118-X-RH REV 1A0

 Original Creation Date: 04/19/00
 Last Update Date: 06/05/00
 Last Major Revision Date: 05/30/00

**SINGLE OPERATIONAL AMPLIFIER, HIGH SPEED: ALSO
 AVAILABLE GUARANTEED TO 30K RAD(SI) TESTED TO
 MIL-STD-883, METHOD 1019.5**

General Description

The LM118 is a precision high speed operational amplifier designed for applications requiring wide bandwidth and high slew rate. It features a factor of ten increase in speed over general purpose devices without sacrificing DC performance.

The LM118 has internal unity gain frequency compensation. This considerably simplifies its application since no external components are necessary for operation. However, unlike most internally compensated amplifiers, external frequency compensation may be added for optimum performance. For inverting applications, feedforward compensation will boost the slew rate to over 150V/us and almost double the bandwidth. Overcompensation can be used with the amplifier for greater stability when maximum bandwidth is not needed. Further, a single capacitor can be added to reduce the 0.1% settling time to under 1 us.

The high speed and fast settling time of these op amps make them useful in A/D converters, oscillators, active filters, sample and hold circuits, or general purpose amplifiers. This device is easy to apply and offers an order of magnitude better AC performance than industry standards such as the LM709.

Industry Part Number

LM118

Prime Die

LM118

NS Part Numbers

 LM118HPQML
 LM118HPQMLV
 LM118J-8PQML
 LM118J-8PQMLV
 LM118WGPQML
 LM118WGPQMLV

Controlling Document

SEE FEATURES SECTION

Processing

MIL-STD-883, Method 5004

Quality Conformance Inspection

MIL-STD-883, Method 5005

Subgrp Description
Temp (°C)

1	Static tests at	+25
2	Static tests at	+125
3	Static tests at	-55
4	Dynamic tests at	+25
5	Dynamic tests at	+125
6	Dynamic tests at	-55
7	Functional tests at	+25
8A	Functional tests at	+125
8B	Functional tests at	-55
9	Switching tests at	+25
10	Switching tests at	+125
11	Switching tests at	-55

Features

- 15 MHz small signal bandwidth
- Guaranteed 50V/uS slew rate
- Maximum bias current of 250nA
- Operates from supplies of $\pm 5V$ to $\pm 20V$
- Internal frequency compensation
- Input and output overload protected
- Pin compatible with general purpose op amps

CONTROLLING DOCUMENTS:

LM118HPQML	5962P9853901QGA
LM118HPQMLV	5962P9853901VGA
LM118J-8PQML	5962P9853901QPA
LM118J-8PQMLV	5962P9853901VPA
LM118WGPQML	5962P9853901QZA
LM118WGPQMLV	5962P9853901VZA

(Absolute Maximum Ratings)

(Note 1)

Supply Voltage		±20V
Power Dissipation (Note 2)		
METAL CAN		750mW
J-8 Pkg		1000mW
CERAMIC SOIC		600mW
Differential Input Current (Note 3)		±10mA
Input Voltage (Note 4)		±15V
Output Short-Circuit Duration		Continuous
Operating Temperature Range		-55 C ≤ Ta ≤ +125 C
Thermal Resistance		
ThetaJA		
Metal Can Pkg	(Still Air @ 0.5W)	160 C/W
	(500LF/Min Air flow @ 0.5W)	86 C/W
J-8 Pkg	(Still Air @ 0.5W)	120 C/W
	(500LF/Min Air flow @ 0.5W)	66 C/W
CERAMIC SOIC	(Still Air @ 0.5W)	198 C/W
	(500LF/Min Air flow @ 0.5W)	124 C/W
ThetaJC		
Metal Can Pkg		48 C/W
J-8 Pkg		17 C/W
CERAMIC SOIC		22 C/W
Storage Temperature Range		-65 C ≤ Ta ≤ +150 C
Lead Temperature (Soldering, 10 seconds)		300 C
Package Weight (Typical)		
METAL CAN		985mg
J-8 Pkg		1090mg
CERAMIC SOIC		225mg
ESD Tolerance (Note 5)		2000V

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions.

Note 2: The maximum power dissipation must be derated at elevated temperatures and is dictated by Tjmax (maximum junction temperature), ThetaJA (package junction to ambient thermal resistance), and TA (ambient temperature). The maximum allowable power dissipation at any temperature is Pdmax = (Tjmax - TA)/ThetaJA or the number given in the Absolute Maximum Ratings, whichever is lower.

Note 3: The inputs are shunted with back-to-back diodes for overvoltage protection. Therefore, excessive current will flow if a differential input voltage in excess of 1V is applied between the inputs unless some limiting resistance is used.

Note 4: For supply voltages less than ±15V, the absolute maximum input voltage is equal to the supply voltage.

Note 5: Human body model, 1.5K ohms in series with 100 pF.

Electrical Characteristics

DC PARAMETERS: (SEE NOTE 6)

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $\pm V_{CC} = \pm 20V$

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS		
Vio	Input Offset Voltage	+Vcc = 35V, -Vcc = -5V, Vcm = -15V			-4	4	mV	1		
					-6	6	mV	2, 3		
		+Vcc = 5V, -Vcc = -35V, Vcm = 15V			-4	4	mV	1		
					-6	6	mV	2, 3		
		Vcm = 0V			-4	4	mV	1		
					-6	6	mV	2, 3		
		+Vcc = 5V, -Vcc = -5V, Vcm = 0V			-4	4	mV	1		
					-6	6	mV	2, 3		
		Iio	Input Offset Current	+Vcc = 35V, -Vcc = -5V, Vcm = -15V, Rs = 100K Ohms	5		-40	40	nA	1
					5		-80	80	nA	2, 3
+Vcc = 5V, -Vcc = -35V, Vcm = 15V, Rs = 100K Ohms	5				-40	40	nA	1		
	5				-80	80	nA	2, 3		
Vcm = 0V, Rs = 100K Ohms	5				-40	40	nA	1		
	5				-80	80	nA	2, 3		
+Vcc = 5V, -Vcc = -5V, Vcm = 0V, Rs = 100K Ohms	5				-40	40	nA	1		
	5				-80	80	nA	2, 3		
Iib+	Input Bias Current			+Vcc = 35V, -Vcc = -5V, Vcm = -15V, Rs = 100K Ohms	5		1	250	nA	1, 2
					5		1	400	nA	3
		+Vcc = 5V, -Vcc = -35V, Vcm = 15V, Rs = 100K Ohms	5		1	250	nA	1, 2		
			5		1	400	nA	3		
		Vcm = 0V, Rs = 100K Ohms	5		1	250	nA	1, 2		
			5		1	400	nA	3		
		+Vcc = 5V, -Vcc = -5V, Vcm = 0V, Rs = 100K Ohms	5		1	250	nA	1, 2		
			5		1	400	nA	3		

Electrical Characteristics

DC PARAMETERS: (SEE NOTE 6) (Continued)

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $\pm V_{CC} = \pm 20V$

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Iib-	Input Bias Current	+Vcc = 35V, -Vcc = -5V, Vcm = -15V, Rs = 100K Ohms	5		1	250	nA	1, 2
			5		1	400	nA	3
		+Vcc = 5V, -Vcc = -35V, Vcm = 15V, Rs = 100K Ohms	5		1	250	nA	1, 2
			5		1	400	nA	3
		Vcm = 0V, Rs = 100K Ohms	5		1	250	nA	1, 2
			5		1	400	nA	3
+Vcc = 5V, -Vcc = -5V, Vcm = 0V, Rs = 100K Ohms	5		1	250	nA	1, 2		
	5		1	400	nA	3		
PSRR+	Power Supply Rejection Ratio	+Vcc = 10V, -Vcc = -20V			-100	100	uV/V	1
					-150	150	uV/V	2, 3
PSRR-	Power Supply Rejection Ratio	+Vcc = 20V, -Vcc = -10V			-100	100	uV/V	1
					-150	150	uV/V	2, 3
CMRR	Common Mode Rejection Ratio	Vcm = $\pm 15V$, Vcc = $\pm 35V$ to $\pm 5V$			80		dB	1, 2, 3
Vio(adj)+	Offset Null				7		mV	1, 2, 3
Vio(adj)-	Offset Null					-7	mV	1, 2, 3
Delta Vio/Delta T	Temperature Coefficient of Input Offset Voltage	25 C \leq TA \leq 125 C	2		-50	50	uV/ C	2
		-55 C \leq TA \leq 25 C	2		-50	50	uV/ C	3
Delta Iio/Delta T	Temperature Coefficient of Input Offset Current	25 C \leq TA \leq 125 C	2		-1000	1000	pA/ C	2
		-55 C \leq TA \leq 25 C	2		-1000	1000	pA/ C	3
Ios+	Short Circuit Current	+Vcc = 15V, -Vcc = -15V, t \leq 25mS, Vcm = -15V			-65		mA	1, 2, 3
Ios-	Short Circuit Current	+Vcc = 15V, -Vcc = -15V, t \leq 25mS, Vcm = 15V				65	mA	1, 2
						80	mA	3
Icc	Power Supply Current	+Vcc = 15V, -Vcc = -15V				8	mA	1
						7	mA	2
						9	mA	3

Electrical Characteristics

DC PARAMETERS: (SEE NOTE 6) (Continued)

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $\pm V_{cc} = \pm 20V$

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
Vopp+	Output Voltage Swing	Rl = 10K Ohms, Vcm = -20V			17		V	4, 5, 6
		Rl = 2K Ohms, Vcm = -20V			16		V	4, 5, 6
Vopp-	Output Voltage Swing	Rl = 10K Ohms, Vcm = 20V				-17	V	4, 5, 6
		Rl = 2K Ohms, Vcm = 20V				-16	V	4, 5, 6
Avs+	Open Loop Voltage Gain	Vout = 15V, Rl = 2K Ohms	1		50		V/mV	4
			1		32		V/mV	5, 6
		Vout = 15V, Rl = 10K Ohms	1		50		V/mV	4
			1		32		V/mV	5, 6
Avs-	Open Loop Voltage Gain	Vout = -15V, Rl = 2K Ohms	1		50		V/mV	4
			1		32		V/mV	5, 6
		Vout = -15V, Rl = 10K Ohms	1		50		V/mV	4
			1		32		V/mV	5, 6
Avs	Open Loop Voltage Gain	$\pm V_{cc} = \pm 5V$, Vout = $\pm 2V$, Rl = 2K Ohms	1		10		V/mV	4, 5, 6
		$\pm V_{cc} = \pm 5V$, Vout = $\pm 2V$, Rl = 10K Ohms	1		10		V/mV	4, 5, 6

Electrical Characteristics

AC PARAMETERS: (SEE NOTE 6)

(The following conditions apply to all the following parameters, unless otherwise specified.)
AC: $\pm V_{cc} = \pm 20V$

SYMBOL	PARAMETER	CONDITIONS	NOTES	PIN-NAME	MIN	MAX	UNIT	SUB-GROUPS
NI(BB)	Noise Input Broadband	BW = 10Hz to 5KHz, $R_s = 0$ Ohms				25	uVrms	7
NI(PC)	Noise Input Popcorn	BW = 10Hz to 5KHz, $R_s = 20K$ Ohms				80	Uvpk	7
TR(tr)	Transient Response: Rise Time	$V_{in} = 50mV$, PRR = 1KHz				40	nS	7, 8A, 8B
TR(os)	Transient Response: Overshoot	$V_{in} = 50mV$, PRR = 1KHz				50	%	7, 8A, 8B
Sr+	Slew Rate	$A_v = 1$, $V_{in} = -5V$ to $+5V$			50		V/uS	7, 8B
					40		V/uS	8A
Sr-	Slew Rate	$A_v = 1$, $V_{in} = +5V$ to $-5V$			50		V/uS	7, 8B
					40		V/uS	8A
ts+	Settling Time	$V_{in} = -5V$ to $+5V$	3, 4			800	nS	9
			3, 4			1200	nS	10, 11
ts-	Settling Time	$V_{in} = +5V$ to $-5V$	3, 4			800	nS	9
			3, 4			1200	nS	10, 11

DC PARAMETERS: DRIFT VALUES

(The following conditions apply to all the following parameters, unless otherwise specified.)
DC: $\pm V_{cc} = \pm 20V$. "Delta calculations performed on JAN S and QMLV devices at group B, subgroup 5 only".

Vio	Input Offset Voltage	$V_{cm} = 0V$			-1	1	mV	1
Iib+	Input Bias Current	$V_{cm} = 0V$, $R_s = 100K$ Ohms			-25	25	nA	1
Iib-	Input Bias Current	$V_{cm} = 0V$, $R_s = 100K$ Ohms			-25	25	nA	1

Note 1: Datalog in K = V/mV.

Note 2: Calculated parameter.

Note 3: Errorband = $\pm 2\%$.

Note 4: Test on Bench, refer to SP-16655.

Note 5: S/S $R_s = 20K$ Ohms, tested with $R_s = 100K$ Ohms for better resolution.

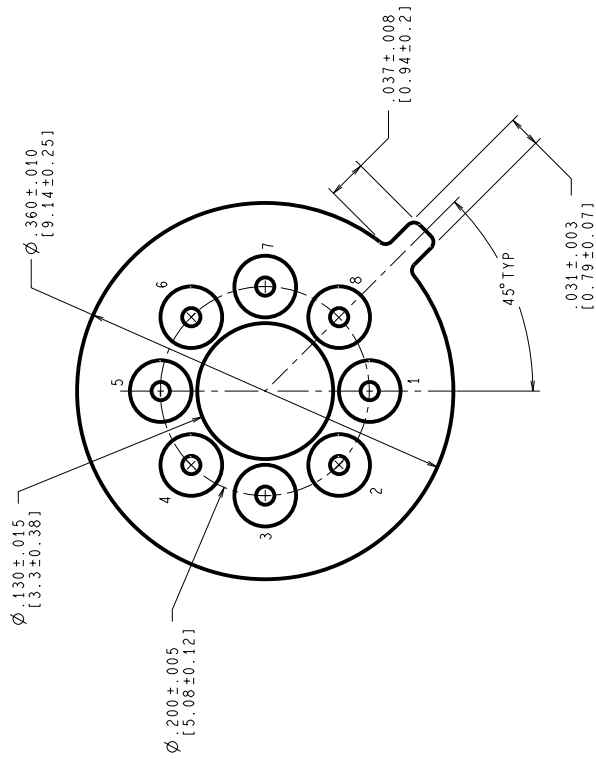
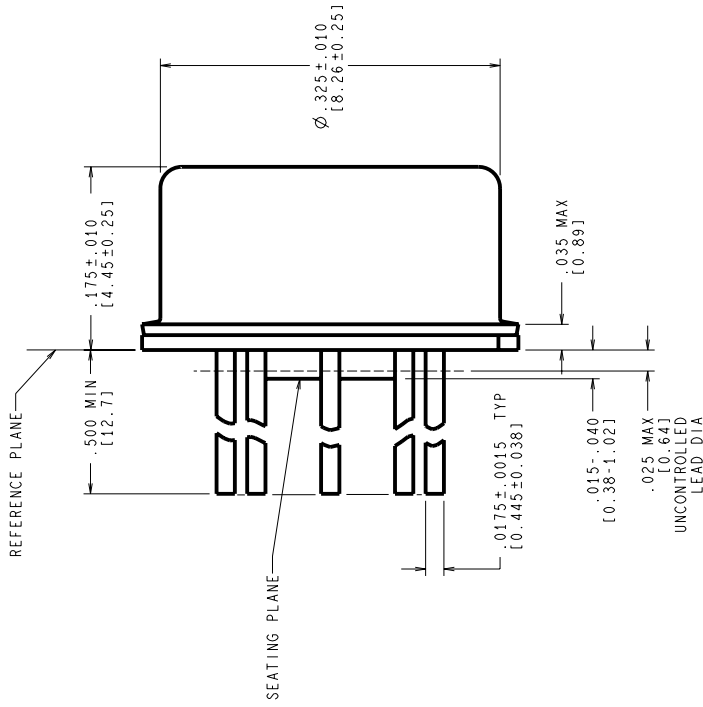
Note 6: Pre and post irradiation limits are identical to those listed under AC and DC electrical characteristics except as listed in the Post Radiation Limits Table. These parts may be dose rate sensitive in a space environment and demonstrate enhanced low dose rate effect. Radiation end point limits for the noted parameters are guaranteed only for the conditions as specified in MIL-STD-883, Method 1019.5, Condition A.

Graphics and Diagrams

GRAPHICS#	DESCRIPTION
05482HRA1	10LD CERPACK, 10LD CERAMIC SOIC (B/I CKT)
09556HR02	CERDIP (J14), CERDIP (J8) (B/I CKT)
09557HRA4	METAL CAN (H), TO-99, 8LD, .200 DIA P.C. (B/I CKT)
H08CRF	METAL CAN (H), TO-99, 8LD, .200 DIA P.C. (P/P DWG)
J08ARL	CERDIP (J), 8 LEAD (P/P DWG)
P000268A	METAL CAN (H), 8 LEAD (PINOUT)
P000315A	CERDIP (J), 8 LEAD (PINOUT)
P000459A	CERAMIC SOIC (WG), 10 LEAD (PINOUT)
WG10ARC	CERAMIC SOIC (WG), 10 LEAD (P/P DWG)

See attached graphics following this page.

REVISIONS			
LTR	DESCRIPTION	E.C.N.	DATE
F	REVISE & REDRAW PER CURRENT STANDARD; UPDATE MIL/AERO STAMP & TITLE.	11002	06/22/95
			MS/



CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

MIL-I-38535
CONFIGURATION CONTROL

NOTES: UNLESS OTHERWISE SPECIFIED

- LEADS TO BE LOCATED WITHIN .007 IN / 0.18 mm OF THEIR TRUE POSITIONS RELATIVE TO A MAXIMUM WIDTH TAB.
- STANDARD METAL CAN TYPE: SOLID BASE WITH CERAMIC STANDOFF.
- APPLIES TO MIL-AERO AND LINEAR PRODUCTS.
- REFERENCE JEDEC REGISTRATION TO-99, JEDEC PUBLICATION No. 95.

APPROVALS	DATE
DRN: MARTA SUCHY	06/22/95
DTG: CHK.	
ENR: CHK.	

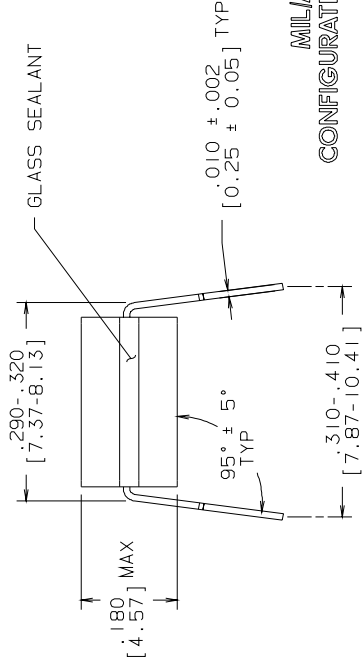
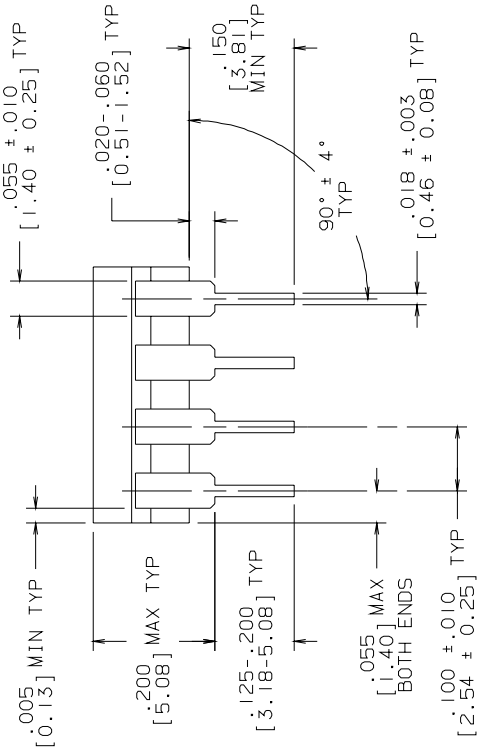
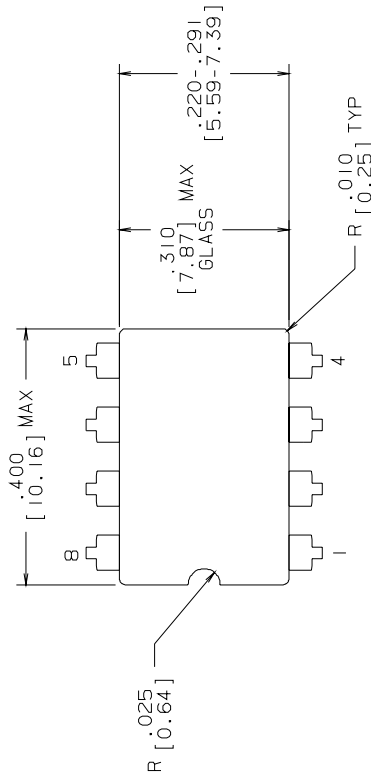
		SCALE	SIZE	DRAWING NUMBER	REV
		N/A	C	MKT-H08C	F

National Semiconductor	
2800 Semiconductor Dr., Santa Clara, CA 95052-8090	
METAL CAN, TO-99, 8 LEAD, .200 DIA P.C.	

DO NOT SCALE DRAWING		SHEET 1 of 1
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REV I S I O N S

LTR	DESCRIPTION	E. C. N.	DATE	BY/APP'D
L	REVISE PER CURRENT STD; REDRAW	10002	09/21/93	TL/



MILAERO
CONFIGURATION CONTROL
MIL-M-38510
CONFIGURATION CONTROL

CONTROLLING DIMENSION: INCH

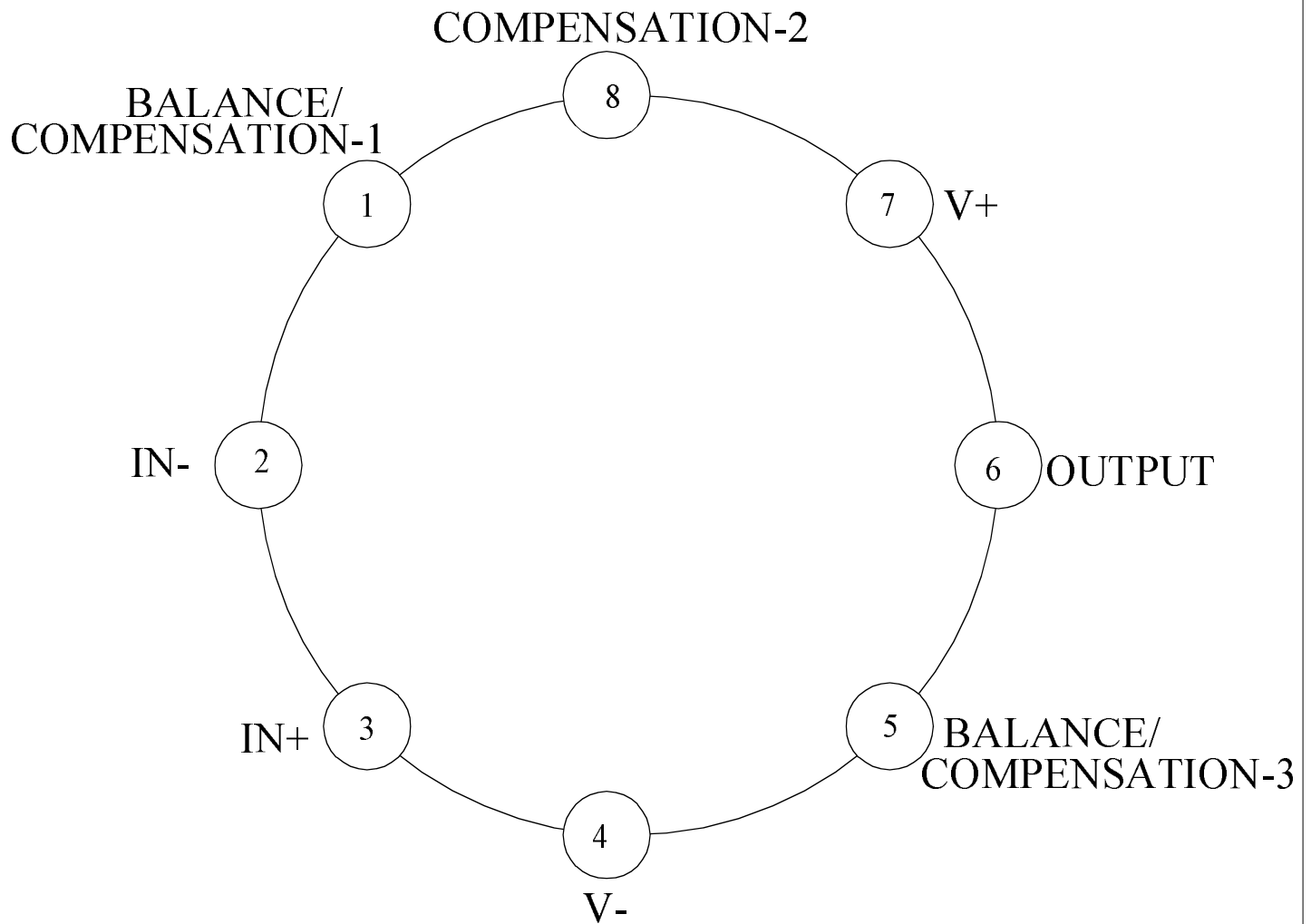
APPROVALS	DATE	APPROVALS	DATE
DRAWN <i>T. LEQUANG</i>	09/21/93	NATIONAL SEMICONDUCTOR CORPORATION	
DFTG. CHK.		2900 Semiconductor Drive, Santa Clara, CA 95052-8090	
ENGR. CHK.			
APPROVAL			

CERDIP (J),
8 LEAD

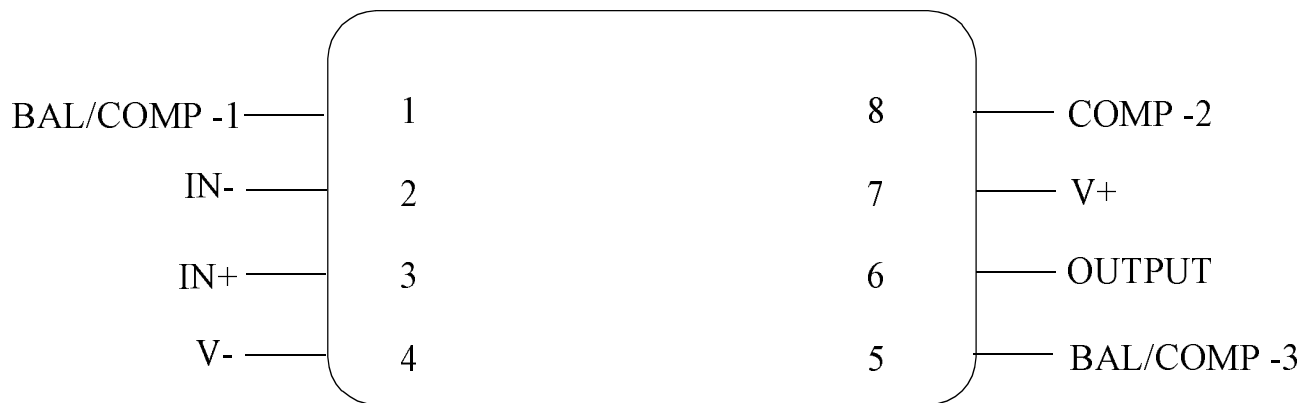
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	DO NOT SCALE DRAWING	SHEET	1	OF 1

NOTES: UNLESS OTHERWISE SPECIFIED

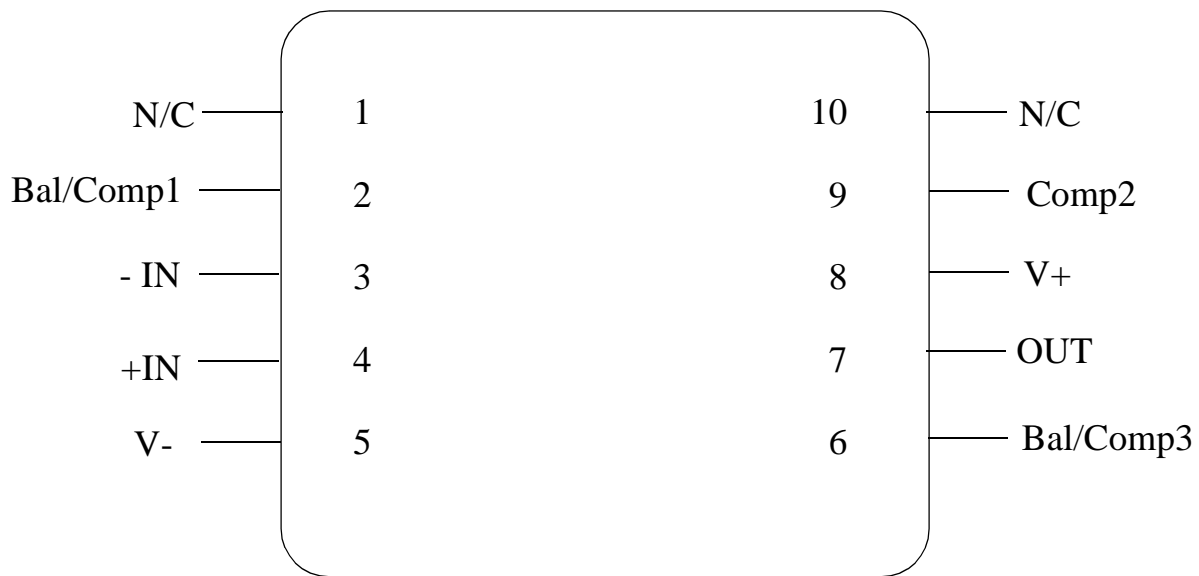
- LEAD FINISH TO BE 200 MICROMETERS / 5.08 MICROMETERS MINIMUM SOLDER MEASURED AT THE CREST OF THE MAJOR FLATS.
- JEDEC REGISTRATION MO-036, VARIATION AA, DATED 04/1981.



LM118H
8 - PIN METAL CAN
CONNECTION DIAGRAM
TOP VIEW
P000268A



LM118J-8
8 - LEAD DIP
CONNECTION DIAGRAM
TOP VIEW
P000315A



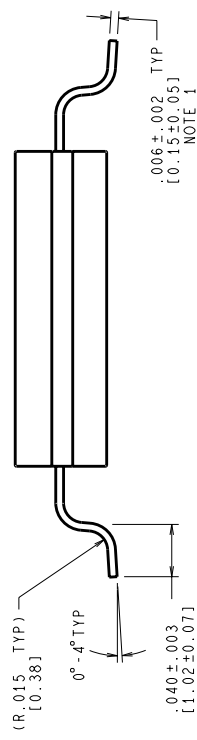
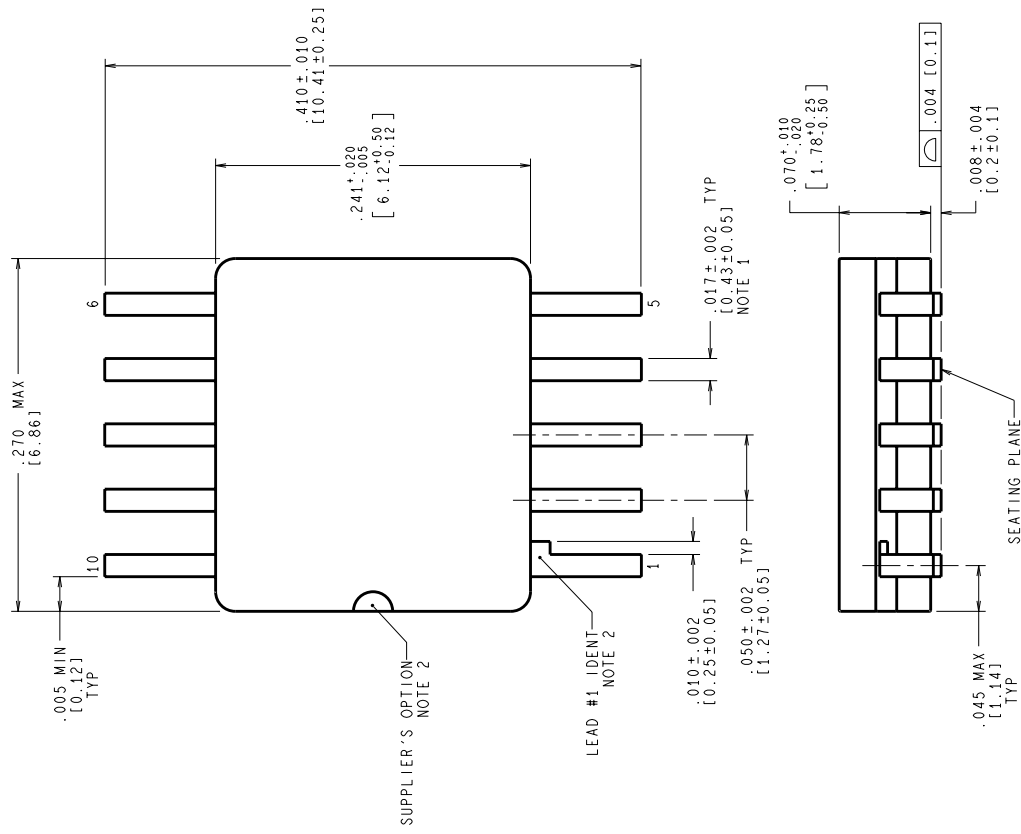
LM118WG
10 - LEAD CERAMIC SOIC
CONNECTION DIAGRAM
TOP VIEW
P000459A



National Semiconductor™
MIL/AEROSPACE OPERATIONS
2900 SEMICONDUCTOR DRIVE
SANTA CLARA, CA 95050

REVISIONS

LTR	DESCRIPTION	E.C.N.	DATE	BY/APP'D
A	RELEASE TO DOCUMENT CONTROL	11374	02/29/1996	MS/KH
B	LD PITCH TOL WAS ±.005; CHANGE LD RADIUS TO REF DIM; REMOVE THE OTHER R.006±.002 DIM. .040±.003 WAS .037±.003	11441	04/19/1996	MS/KH
C	R .015(0.38) WAS R .006(0.15)	11838	10/08/1997	TL/



CONTROLLING DIMENSION IS INCH
VALUES IN | | ARE MILLIMETERS

MIL-PRF-38535
CONFIGURATION CONTROL

NOTES: UNLESS OTHERWISE SPECIFIED

- LEAD FINISH: SOLDER DIPPED WITH Sn60 OR Sn63 SOLDER CONFORMING TO MIL-PRF-38535 TO A MINIMUM THICKNESS OF 200 MICRONS/ 5.08 MICROMETERS. SOLDER MAY BE APPLIED OVER LEAD BASIS METAL OR Sn PLATE. MAXIMUM LIMIT MAY BE INCREASED BY .003 IN/ 0.08mm AFTER LEAD FINISH APPLIED.
- LEAD 1 IDENTIFICATION SHALL BE:
 - A NOTCH OR OTHER MARK WITHIN THIS AREA
 - A TAB ON LEAD 1, EITHER SIDE
- NO JEDEC REGISTRATION AS OF FEBRUARY 1996.

APPROVALS	DATE	SCALE	SIZE	DRAWING NUMBER	REV
DRN: MARYA SUCHY	02/29/96	N/A	C	(SC)MKT-WG10A	C
DATE: 02/29/96					
CHK: [Signature]					
PROJECTION					
NATIONAL SEMICONDUCTOR 2800 Semiconductor Dr., Santa Clara, CA 95052-8090					
CERPACK, 10 LEAD, GULL WING					
DO NOT SCALE DRAWING SHEET 1 of 1					

Revision History

Rev	ECN #	Rel Date	Originator	Changes
0A0	M0003680	06/05/00	Rose Malone	Initial MDS Release: MRLM118-X-RH, Rev. 0A0
1A0	M0003718	06/05/00	Rose Malone	Update MDS: MRLM118-X-RH, Rev. 0A0 to MRLM118-X-RH, Rev. 1A0. Removed subgroups 12, 13 and 14 from Main Table. Changed Subgroups on ts+ and ts- parameters from 12, 13, 14 to 9, 10, 11. Changed to meet DSCC requirements.